

# LSI Design and MDT Electronics

Oct. 26, 2000  
ATLAS EC Trigger WS  
@Kyoto

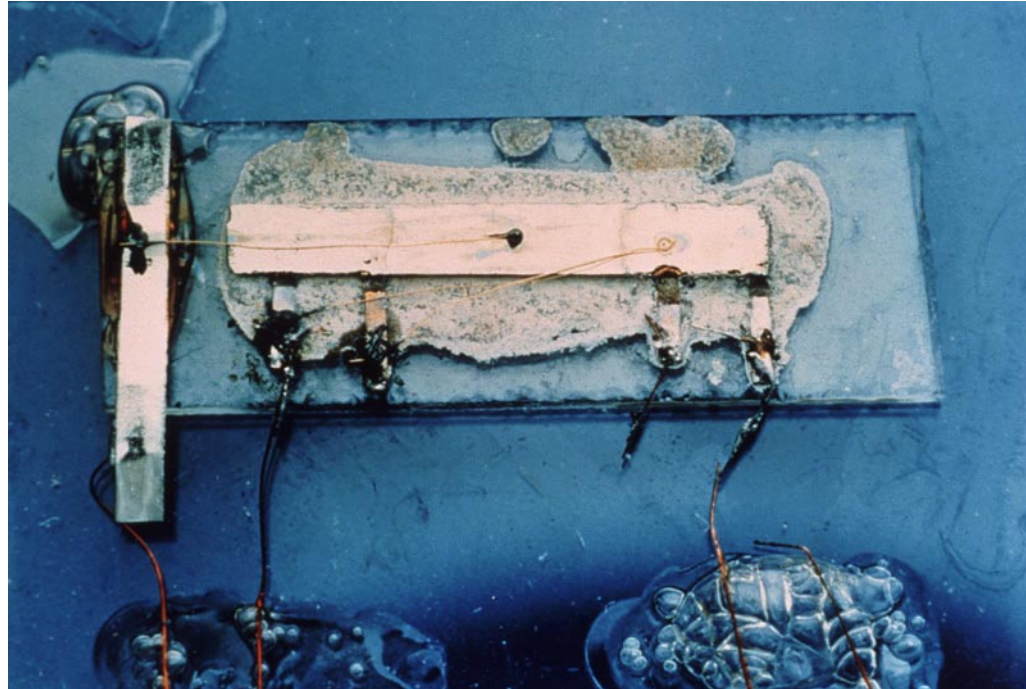
*Yasuo Arai (KEK)*  
*yasuo.arai@kek.jp*  
*<http://atlas.kek.jp/~arai/>*

I'm not working on TGC Electronics,  
but I'd like to show you something about

LSI Design  
MDT Frontend Electronics  
ATLAS Muon TDC

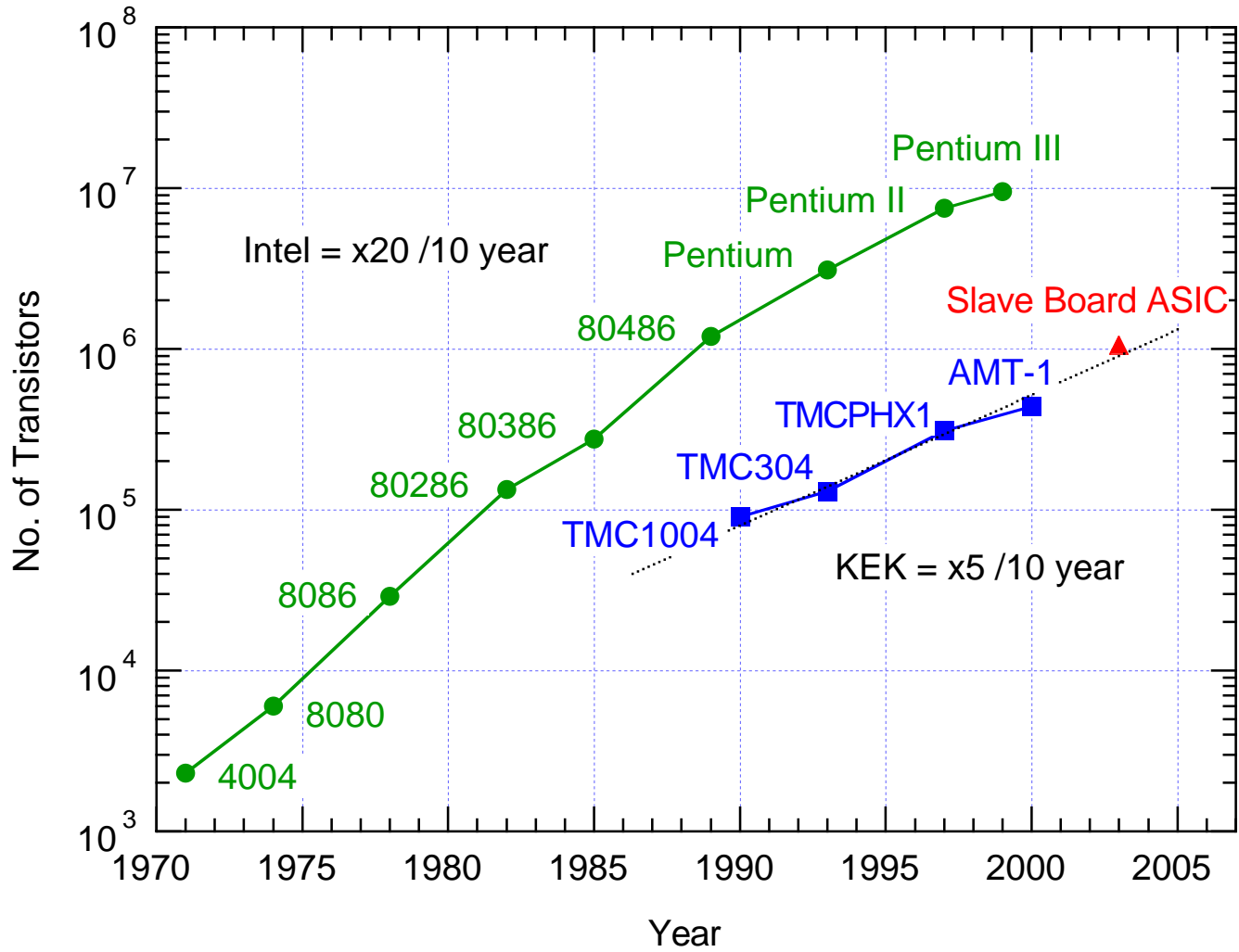
## First Integrated Circuit

Nobel Prize in Physics, Jack Kilby,  
the invention of the integrated circuit.



A transistor and other components on a slice of germanium,  
7/16-by-1/16-inches in size. (1958)

# Moore's Law

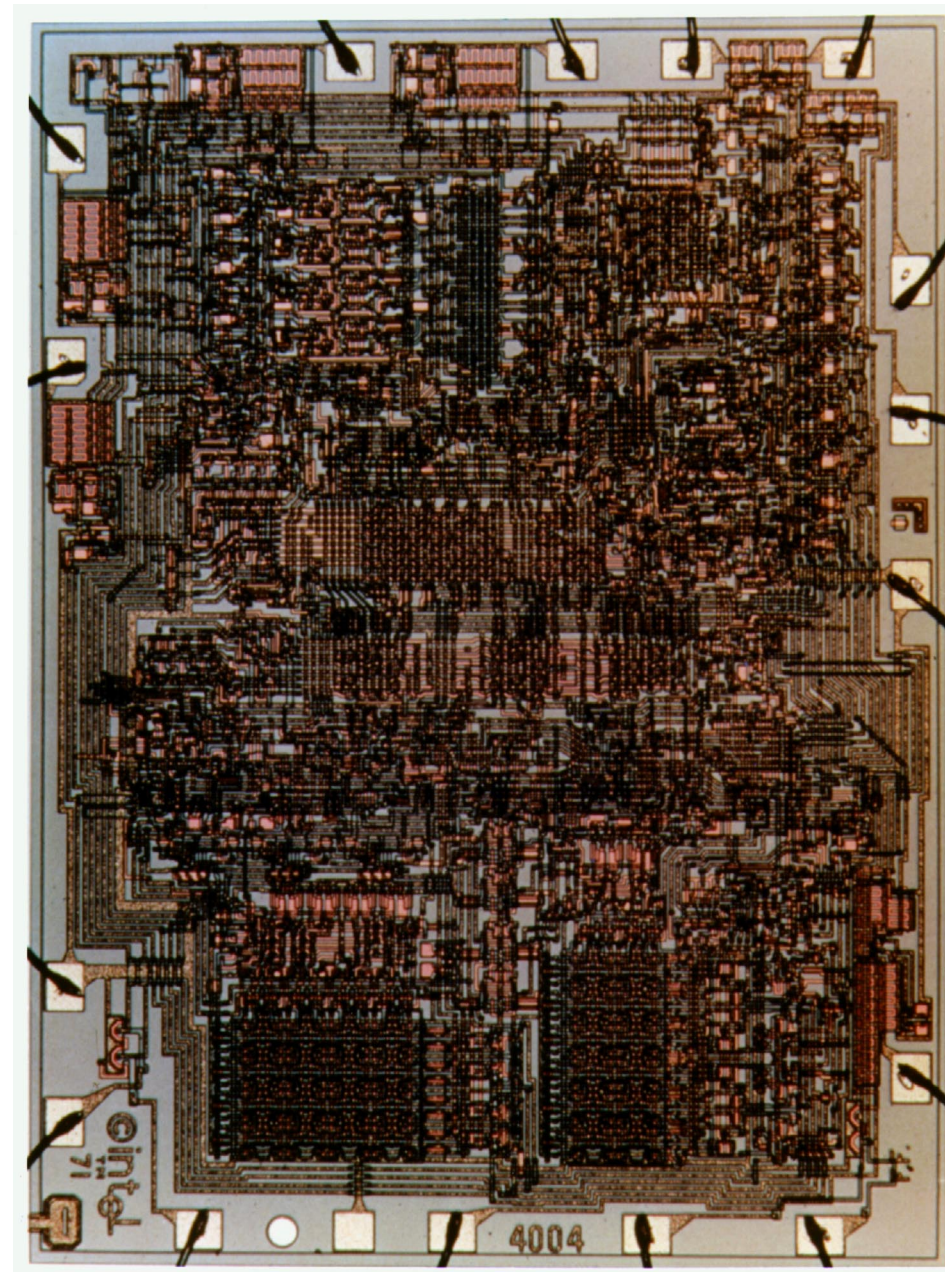


# First Microprocessor

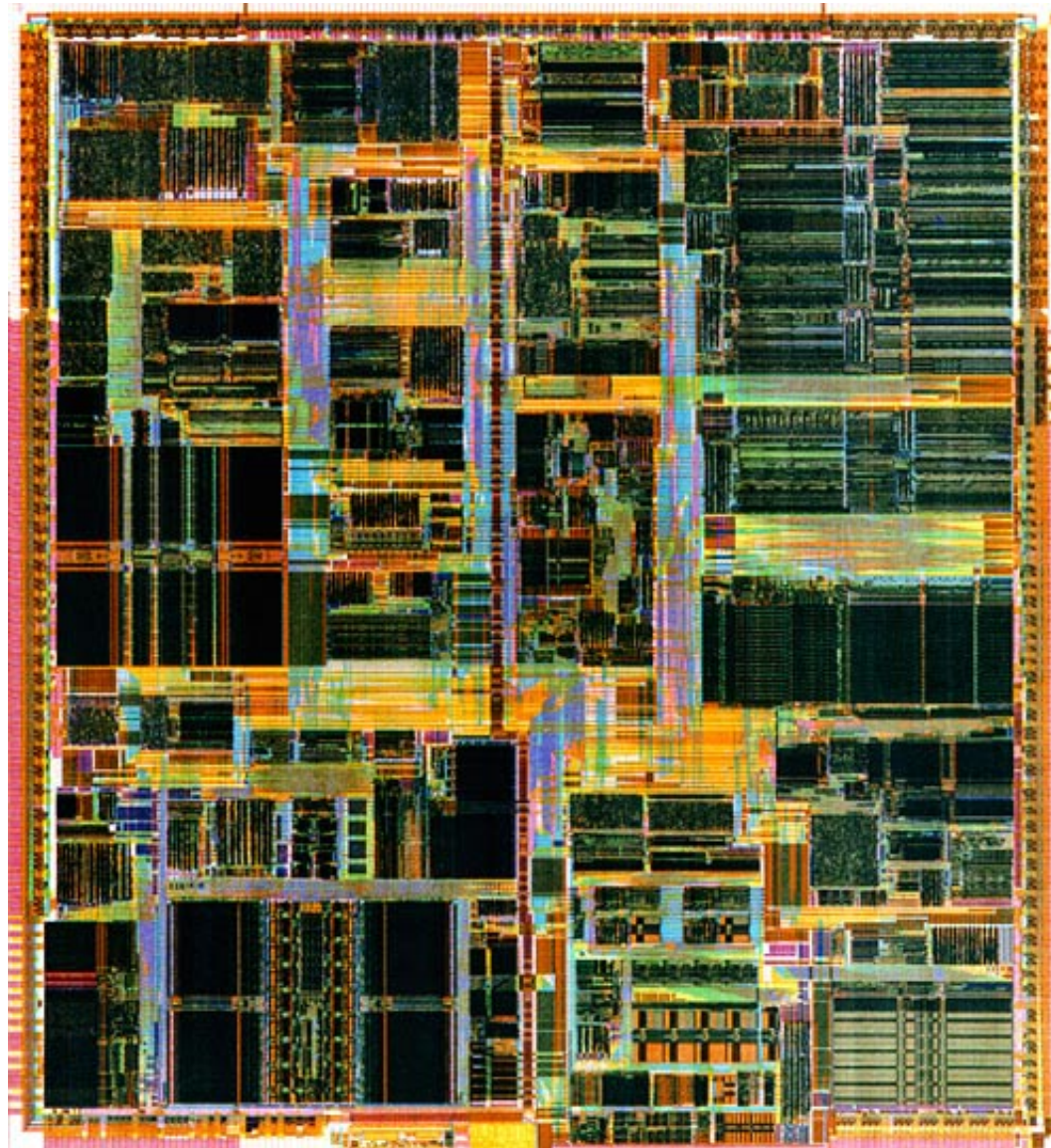
Year 1971

2300 transistors

10  $\mu\text{m}$  technology

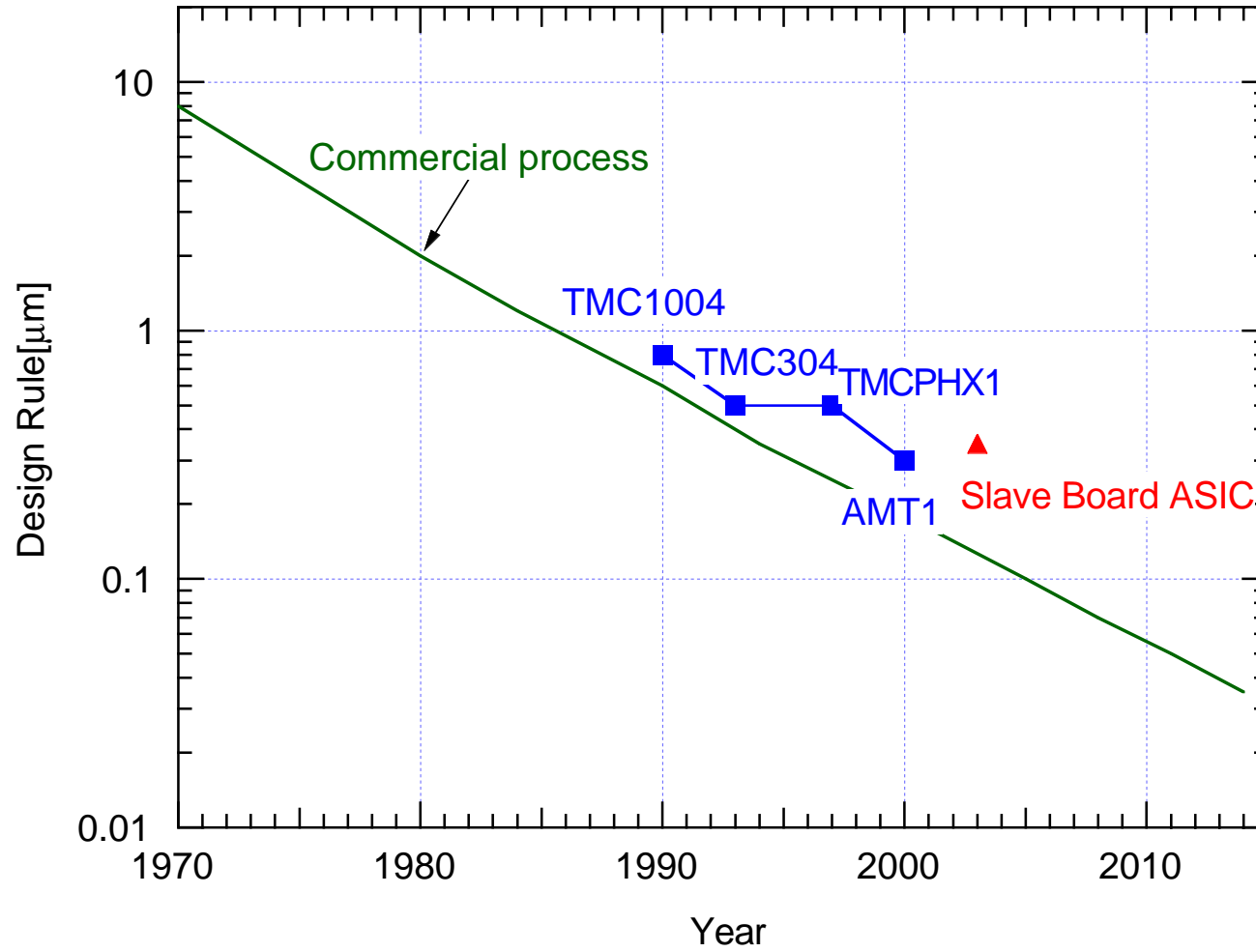


Then ....

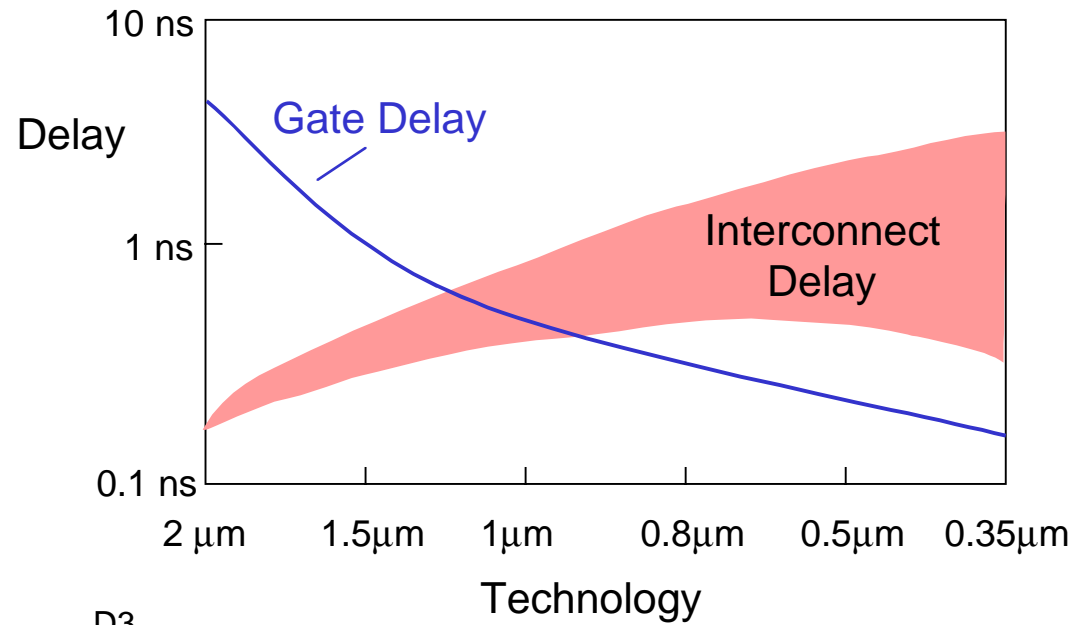


Pentium II

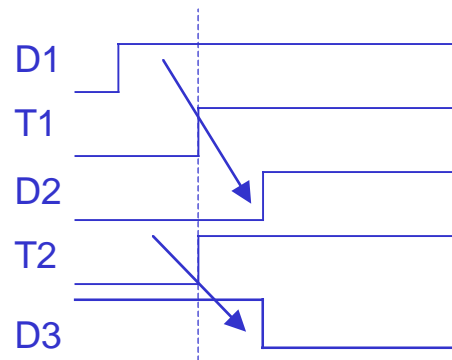
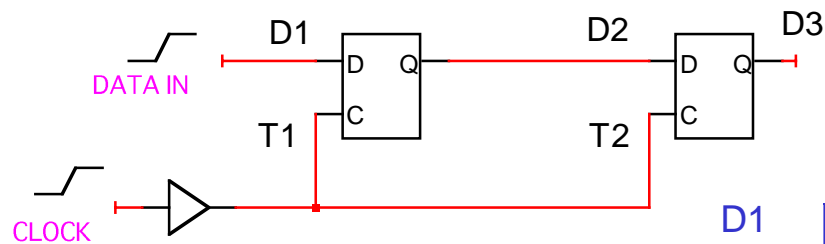
# CMOS Process Technology



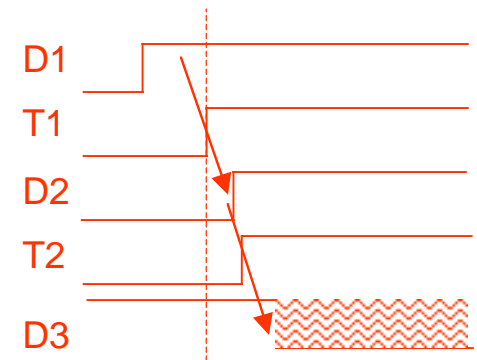
# Gate Delay and Interconnect Delay



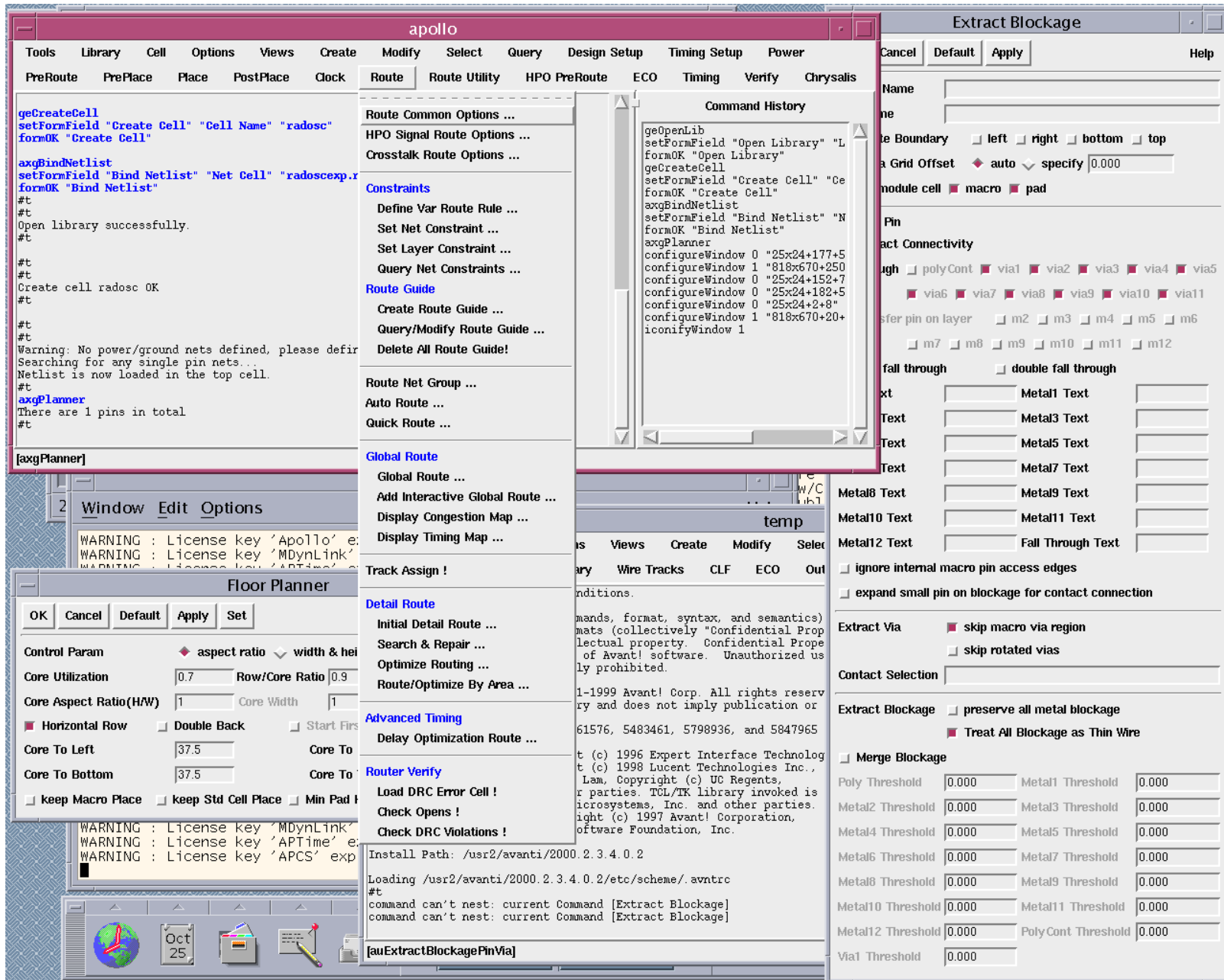
Simple Shift Register



Good Old Days



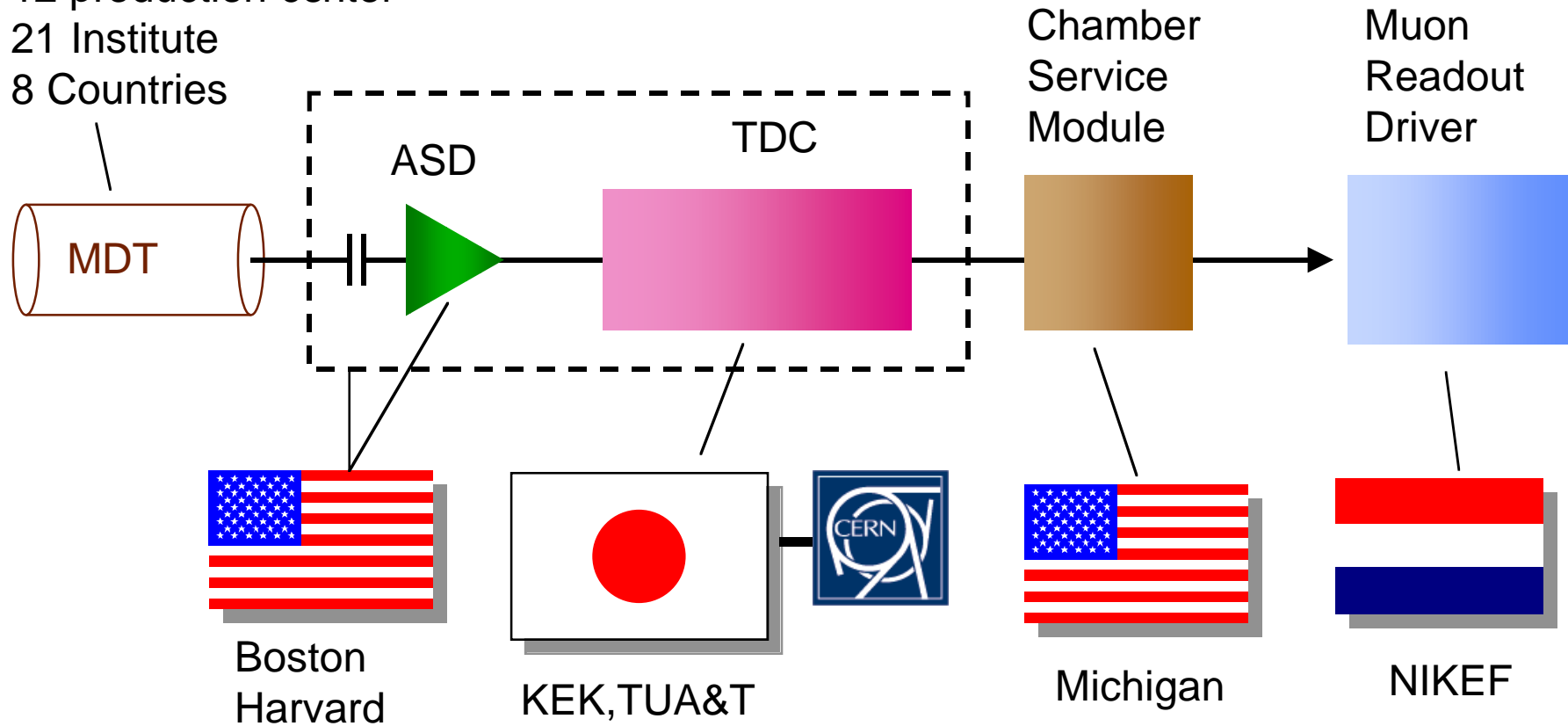
Nowadays

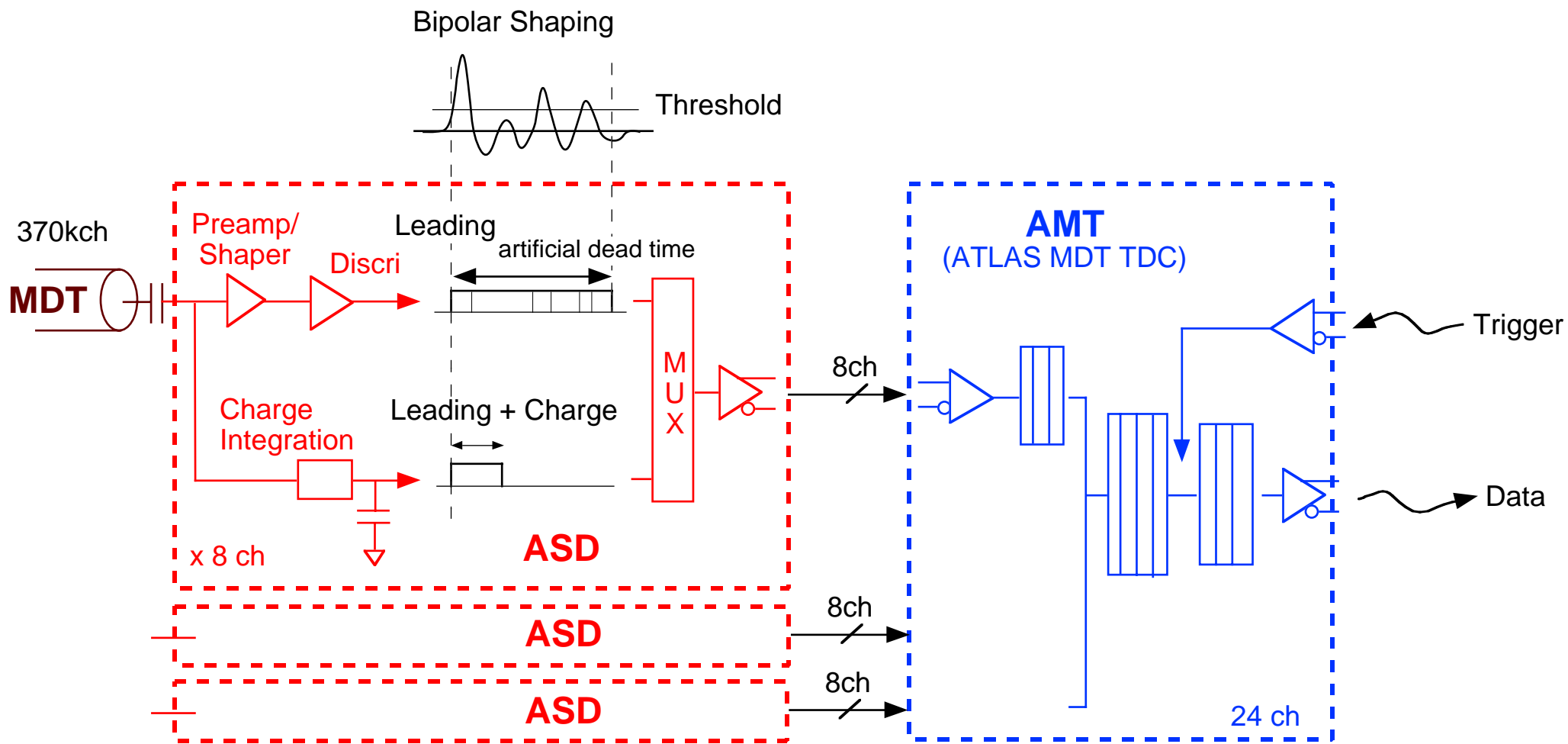




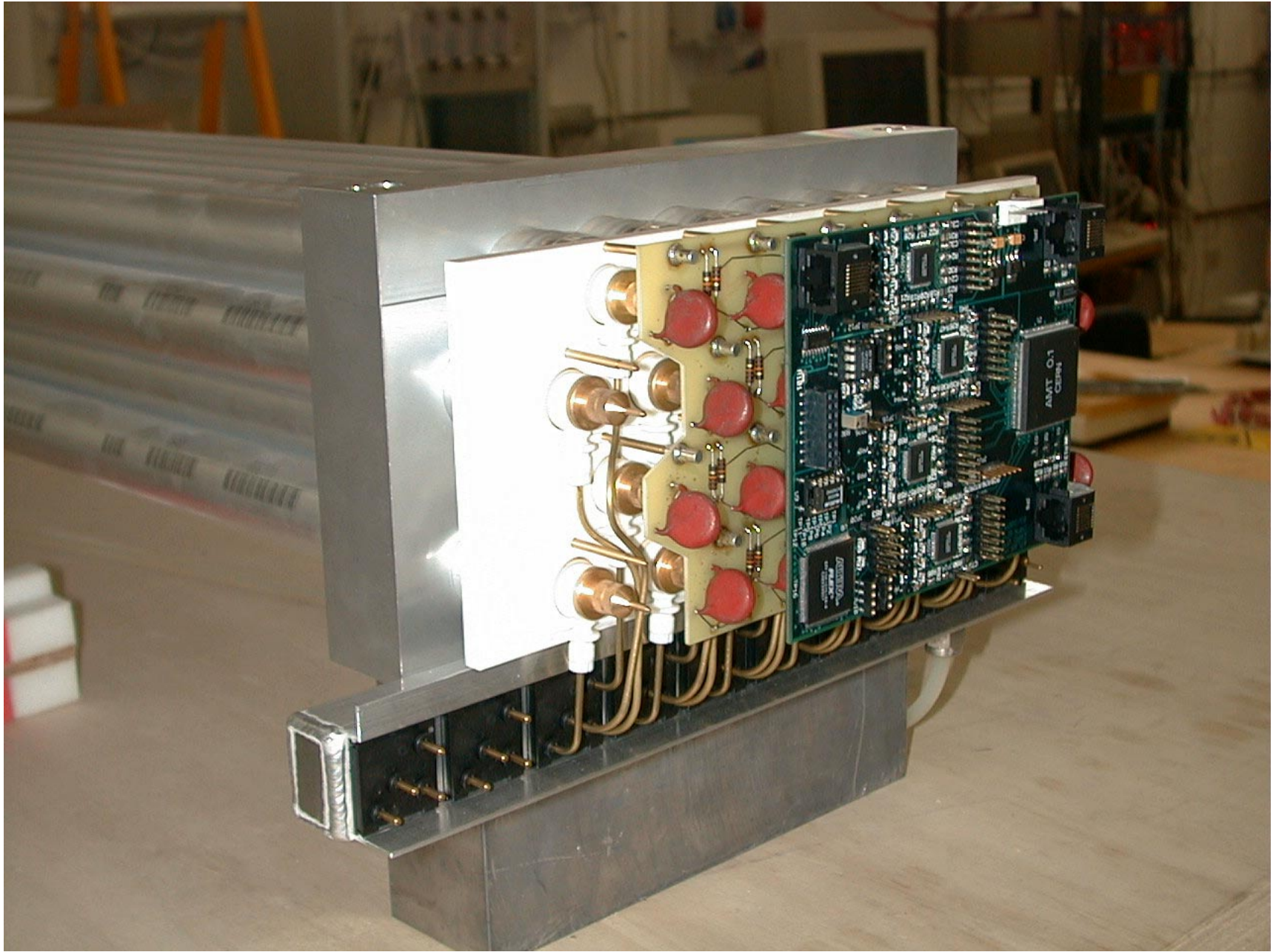
# MDT Electronics Collaboration

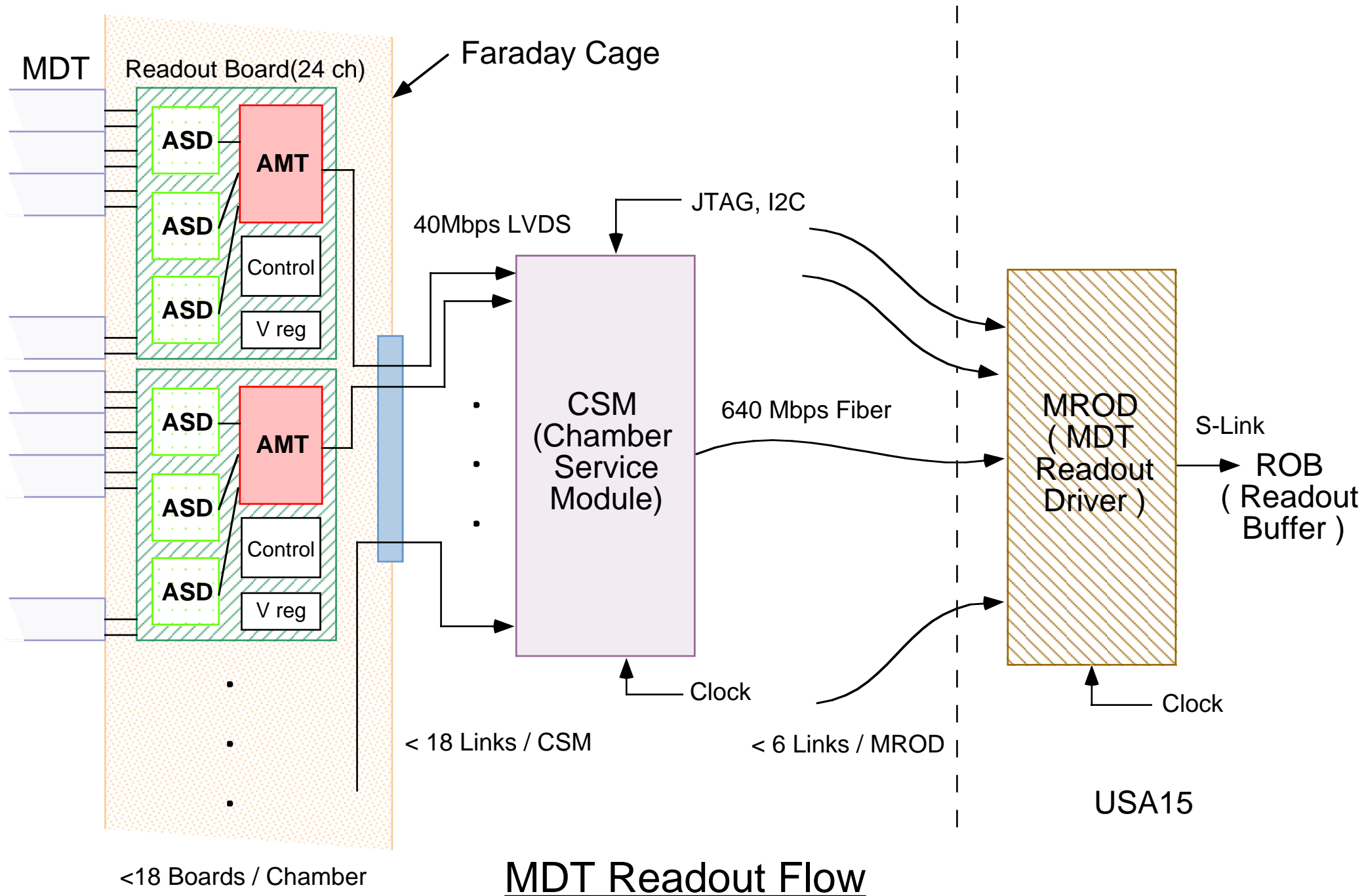
12 production center  
21 Institute  
8 Countries

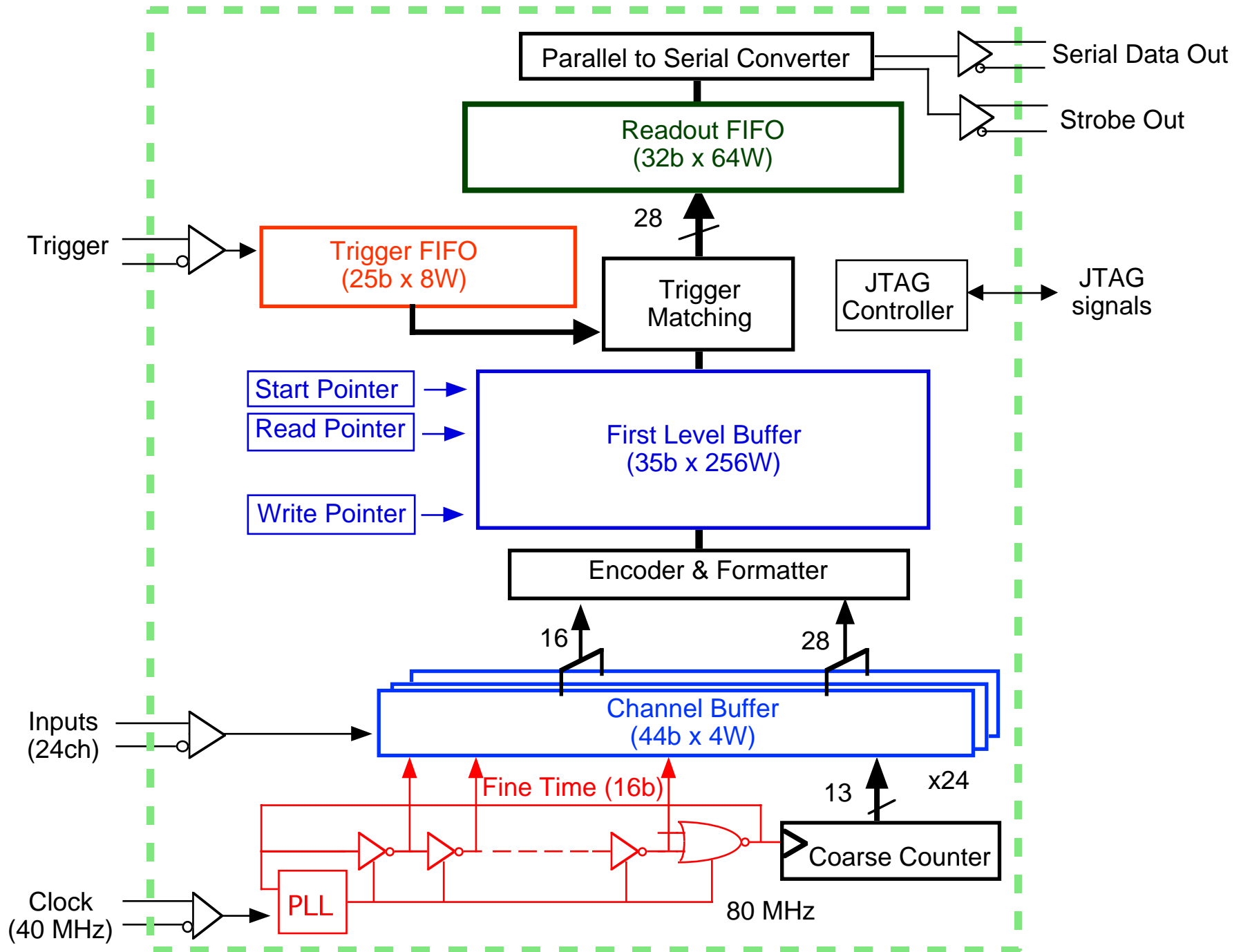




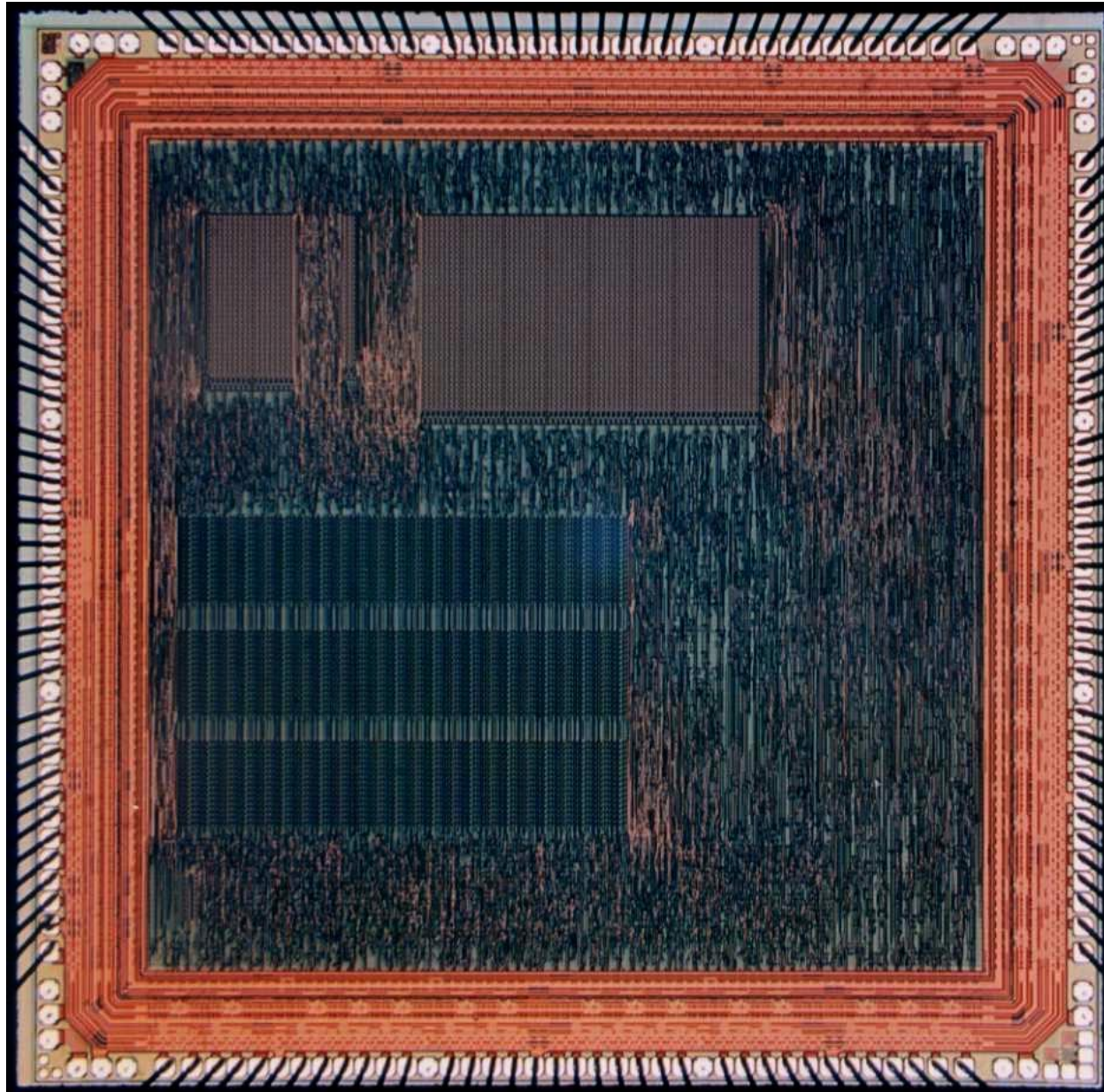
## ATLAS MDT Frontend Electronics







**Block Diagram of the ATLAS Muon TDC**

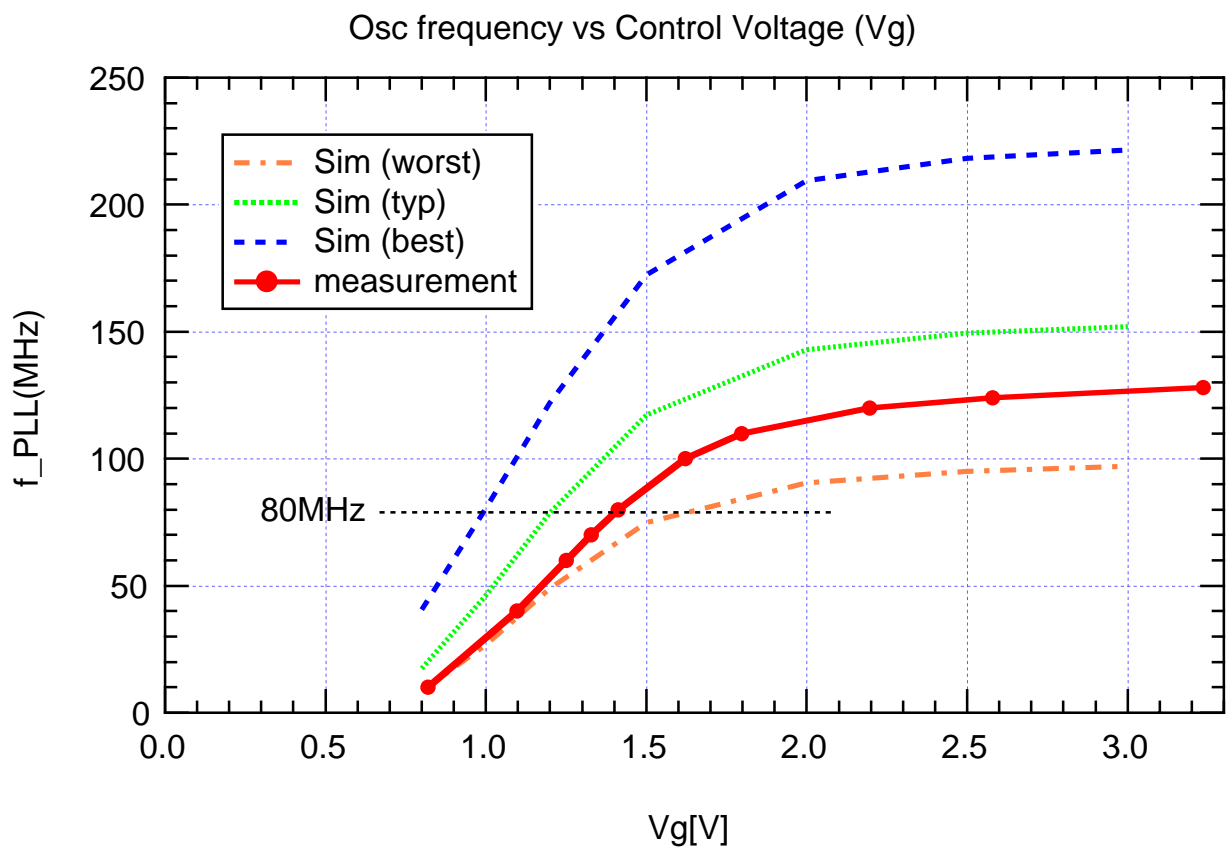
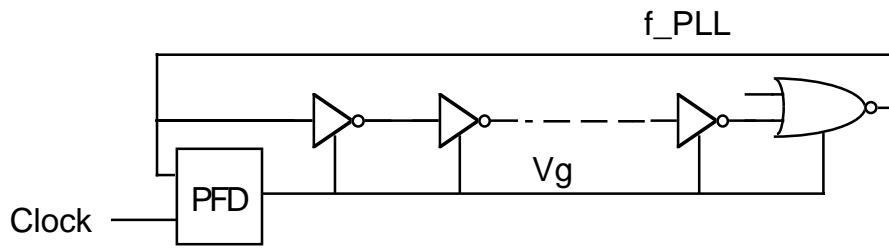


***Photograph of the AMT-1 chip***

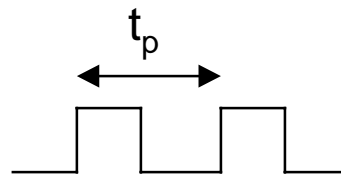
## Development of ATLAS MDT TDC (AMT)

- ~370 k channels, 400 kHz input rate, 100 kHz trigger rate.
  - Sub-ns timing resolution.
  - Leading and trailing edge time measurement.
  - Low-cost, Low-power & High-density (24 ch/chip).
  - LVDS interface, JTAG control.
  - Radiation Tolerant ( $\sim 11$  krad,  $1.2 \times 10^{13}$  n/cm<sup>2</sup>).
- ➔ Design study in collaboration with CERN/EP -MIC group.
- ➔ Quick test chip (AMT-0) in a 0.7  $\mu\text{m}$  process.(10 kch)
- ➔ Develop a test element group chip (AMT-TEG) in a new 0.3  $\mu\text{m}$  process (Toshiba Gate-Array) which will be used in a final chip.
- ➔ Circuit performance test and radiation tolerance test was done.

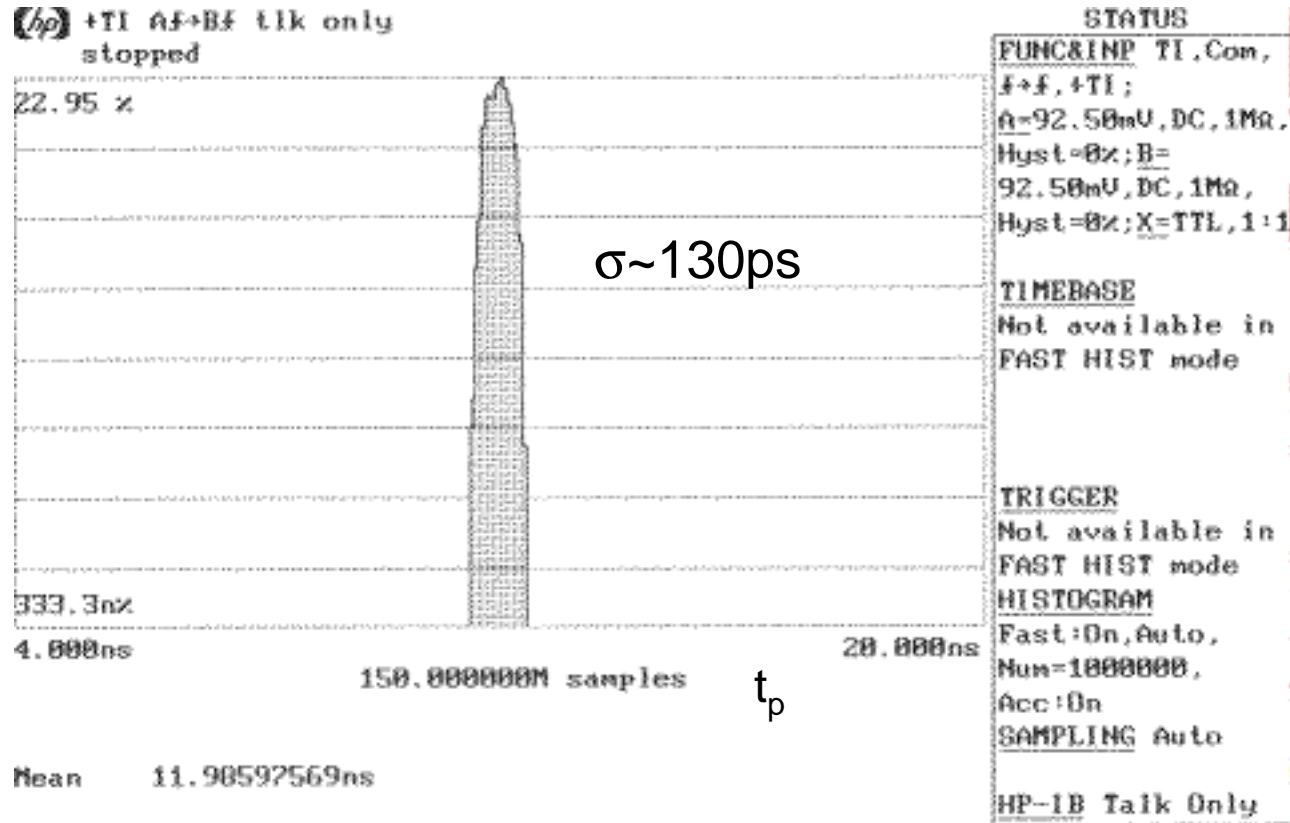
# Voltage Controlled Ring Oscillator



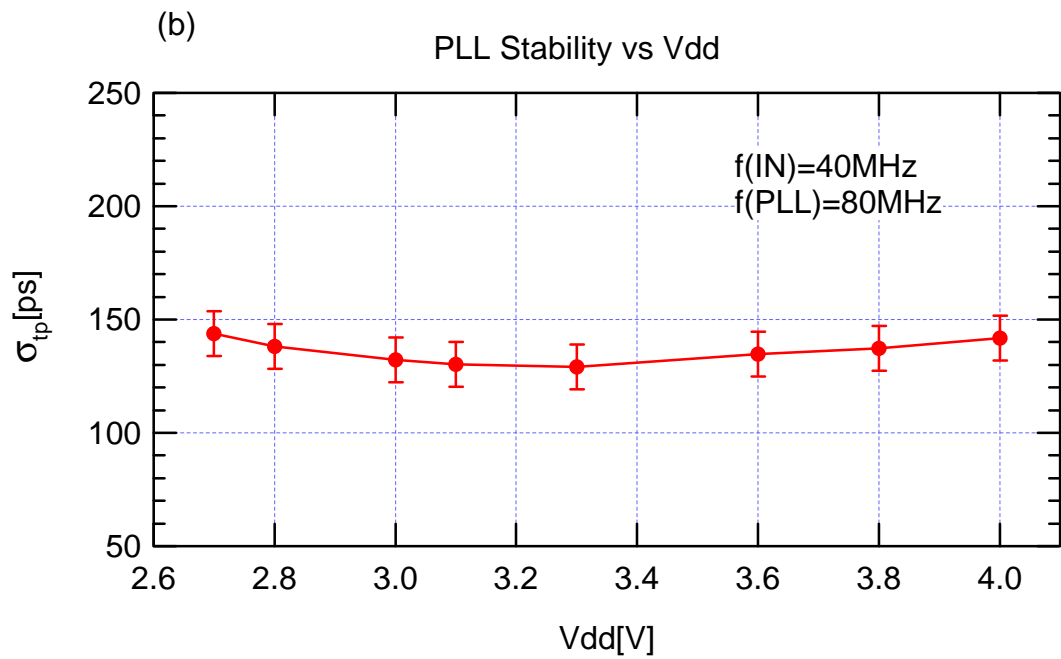
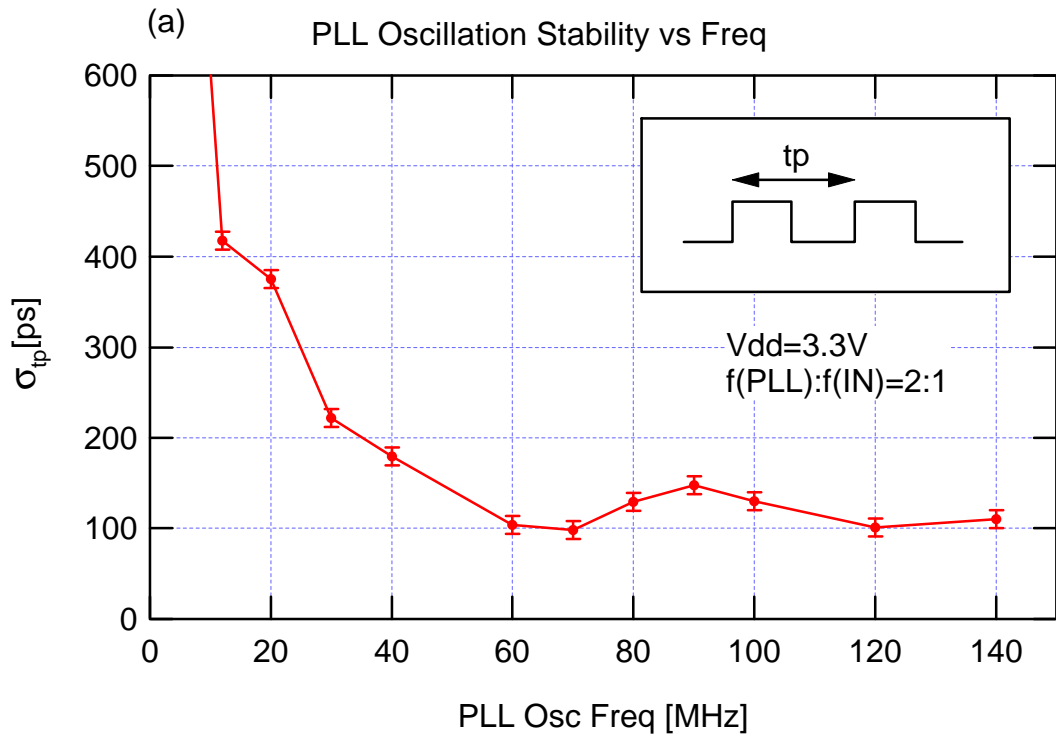




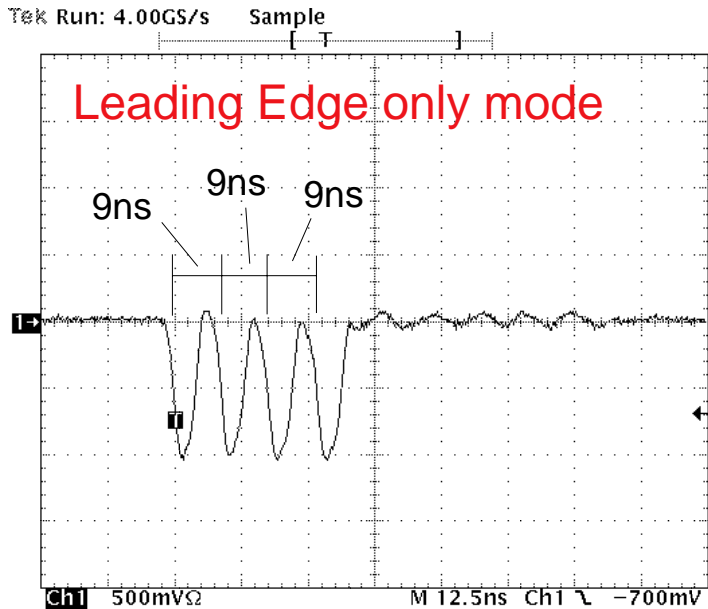
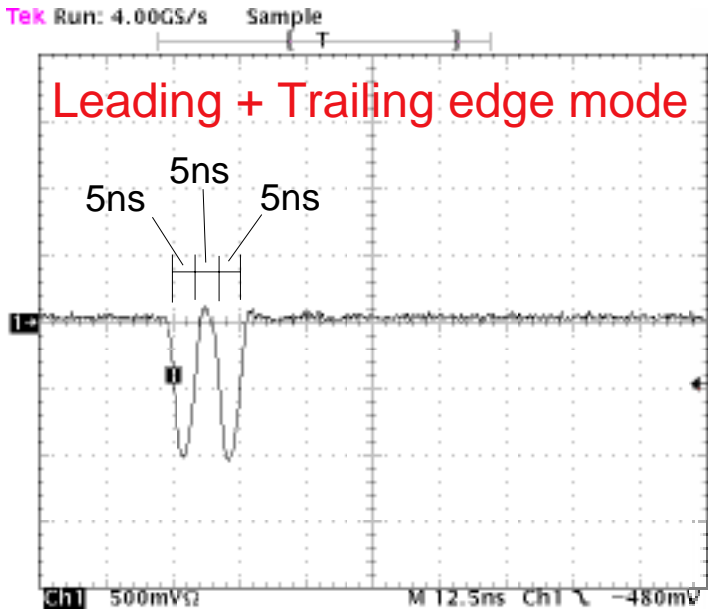
$f_{PLL} = 80 \text{ MHz}$   
 $V_{dd} = 3.3 \text{ V}$



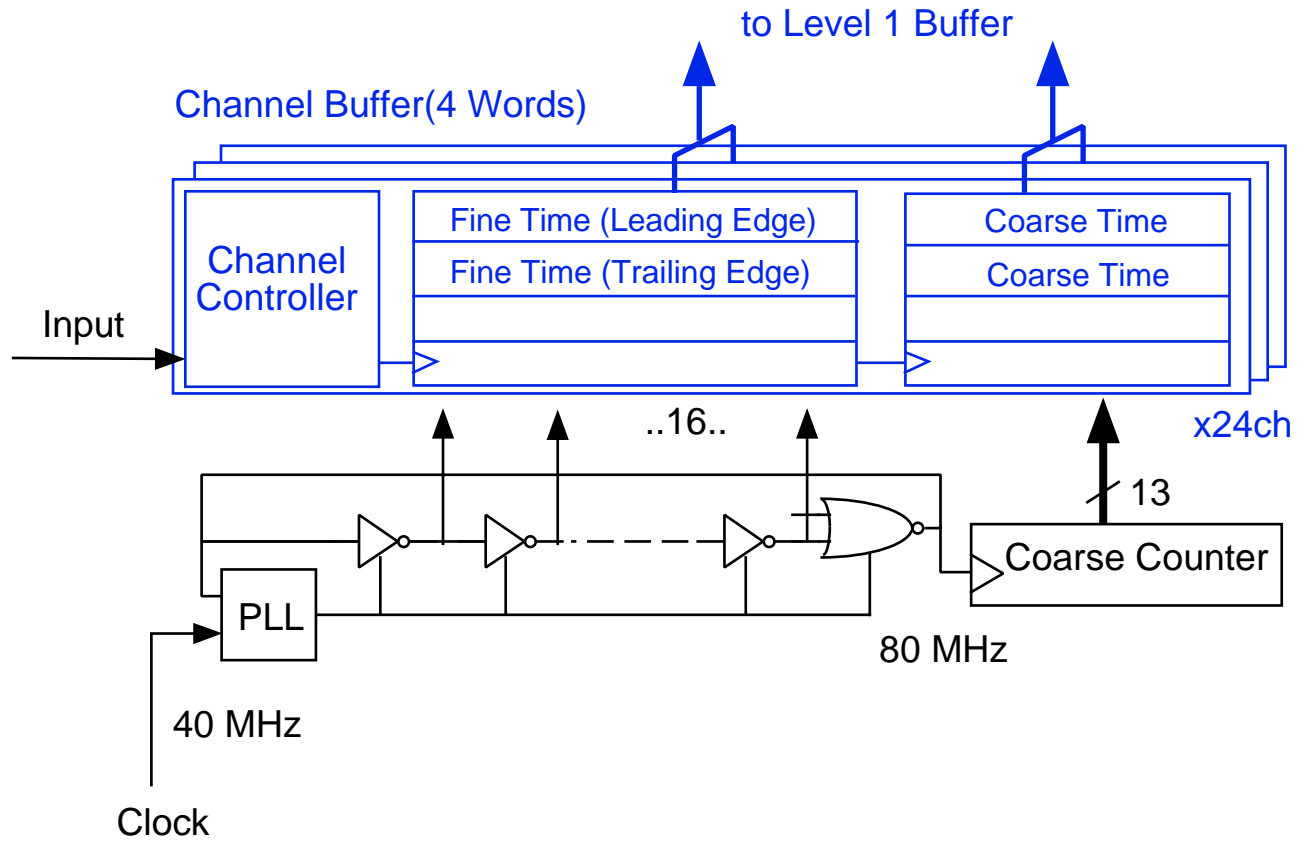
## PLL Oscillation Jitter Histogram



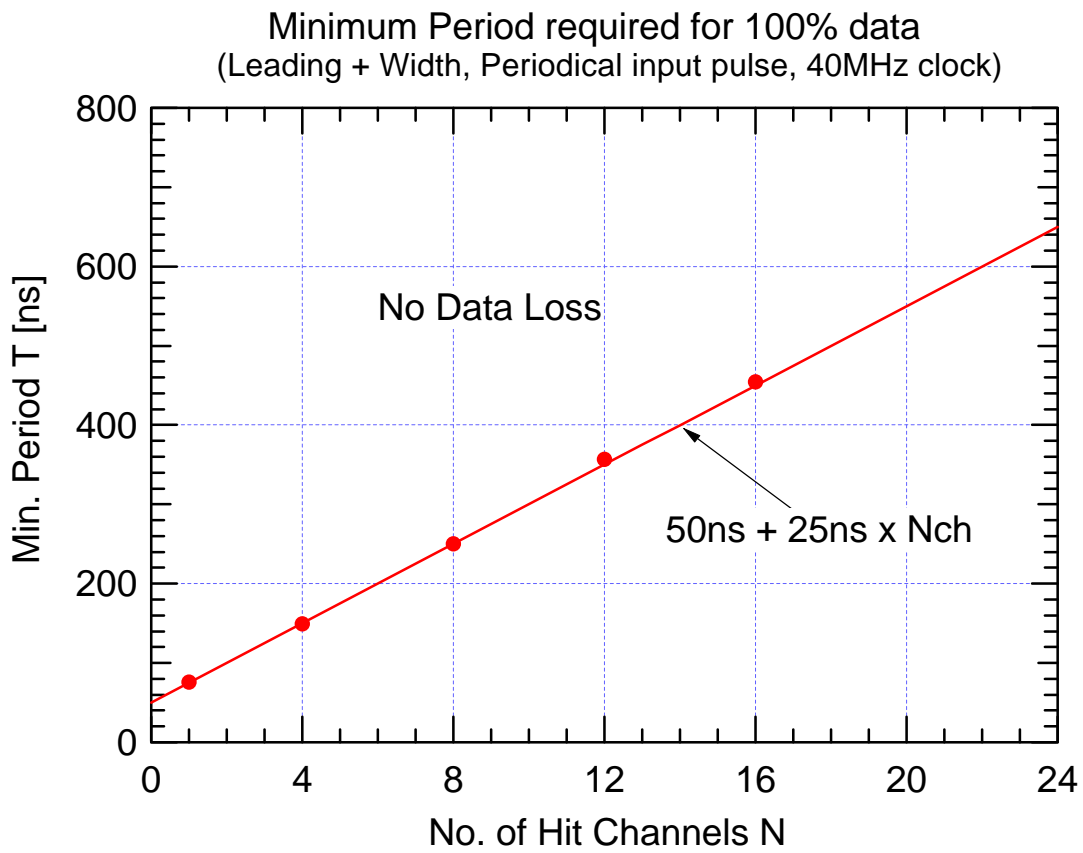
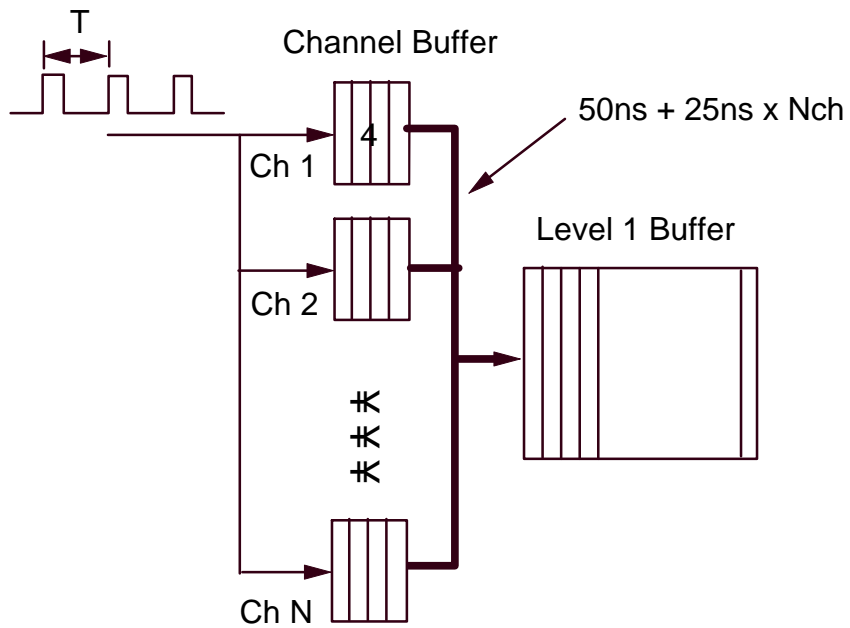
# Channel Buffer Speed



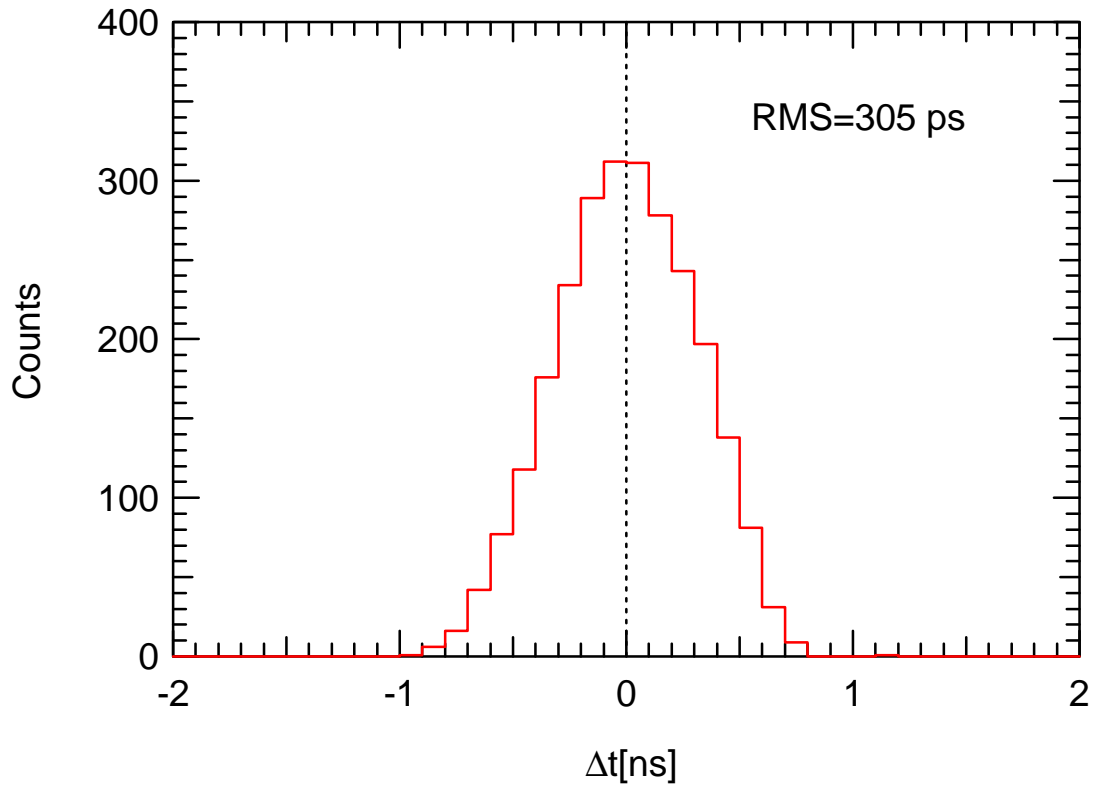
Multiple Edge Resolution = 5 ns (Double Edge)  
= 9 ns (Single Edge)



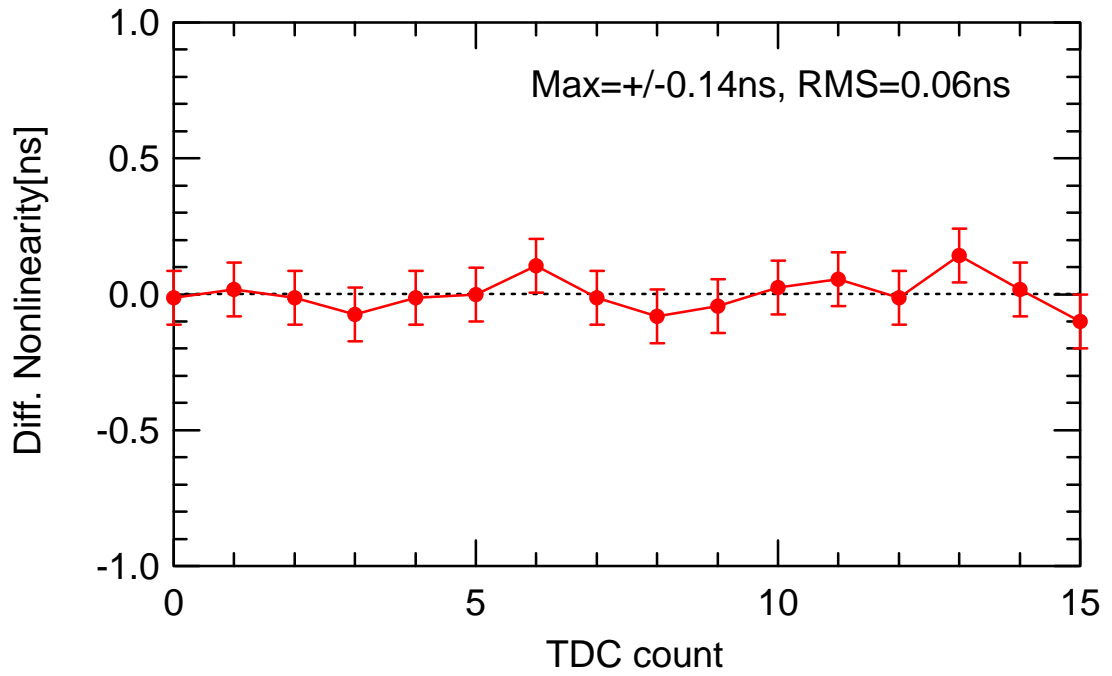
## Data Transfer Rate to L1 Buffer



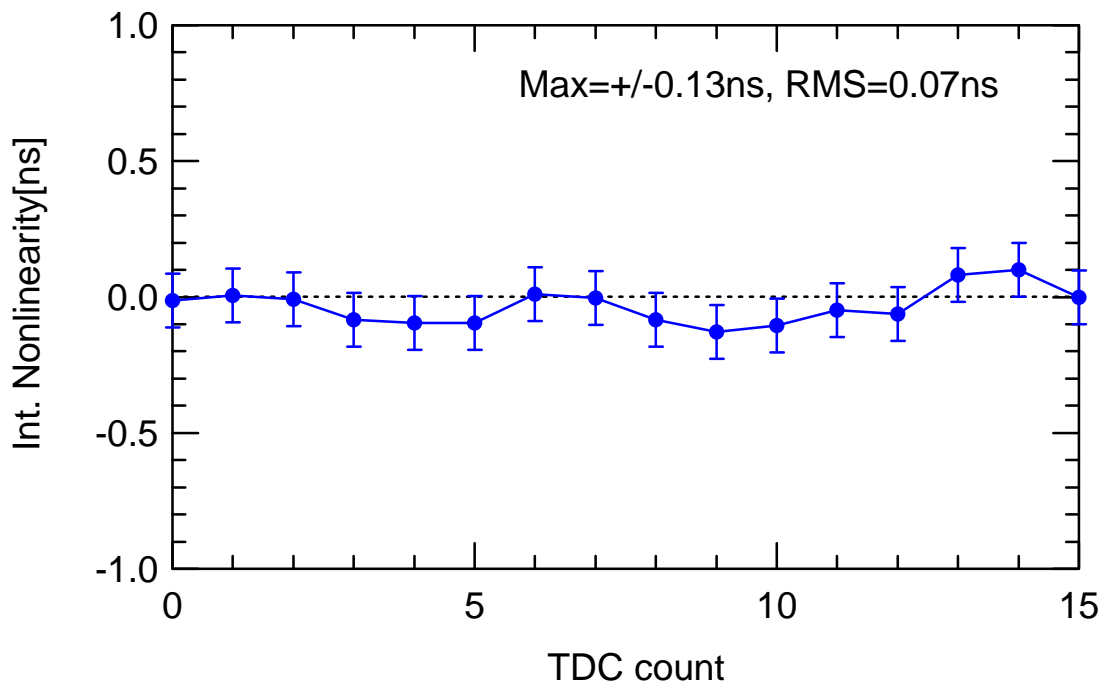
### AMT-TEG1 Timing Resolution



AMT-TEG1 Differential Nonlinearity

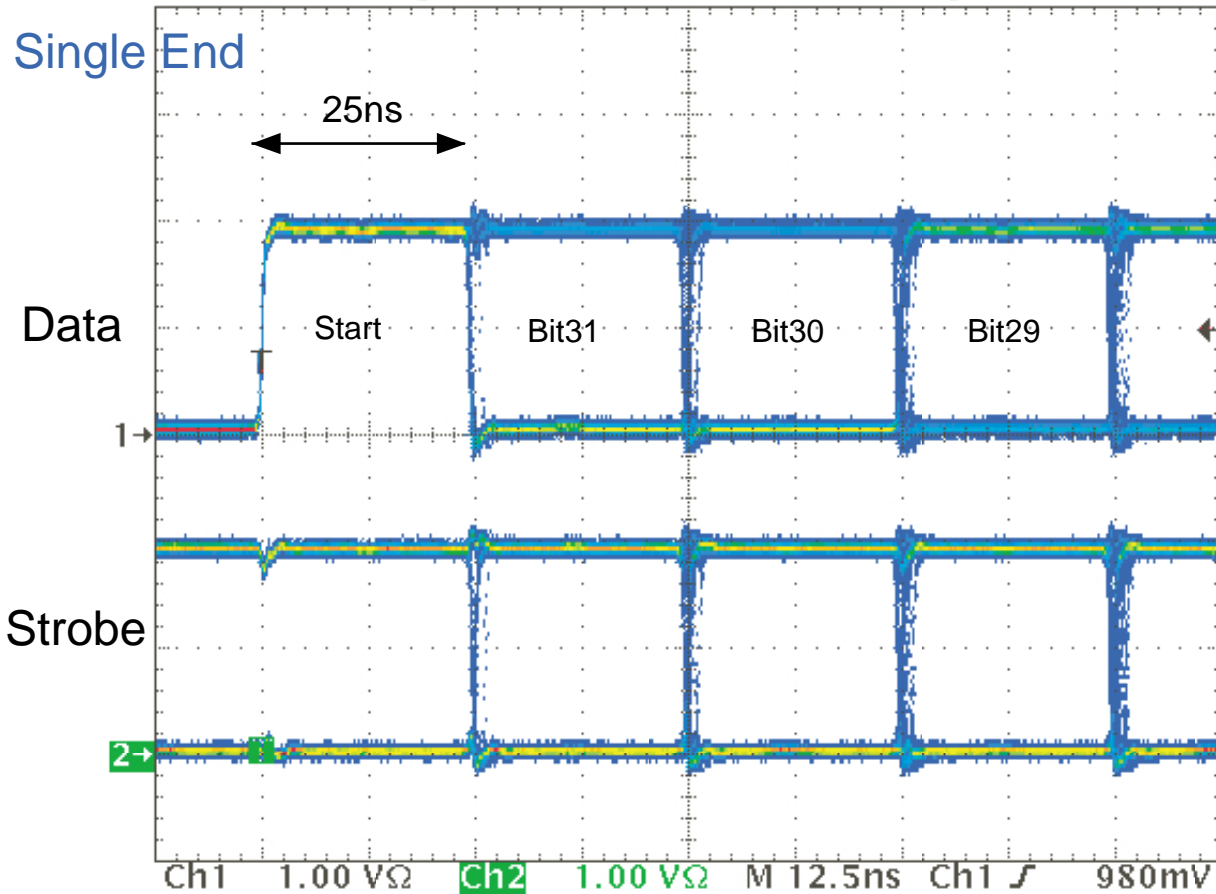


AMT-TEG1 Integral Nonlinearity



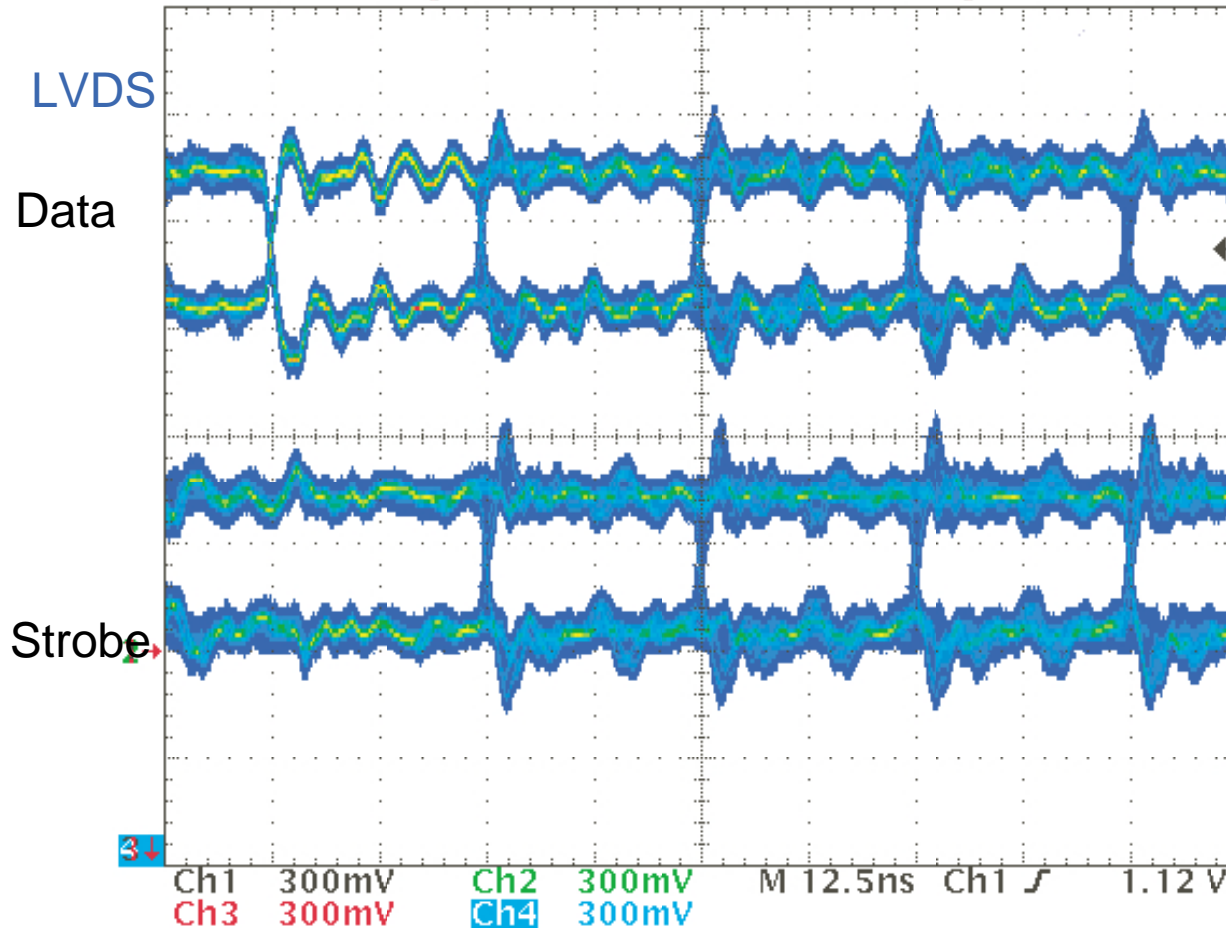
# LVDS Serial Output

Tek Stop: 4.00GS/s ET 211412 Acqs DPO Brightness: 4 %



25 Apr 2000  
16:26:38

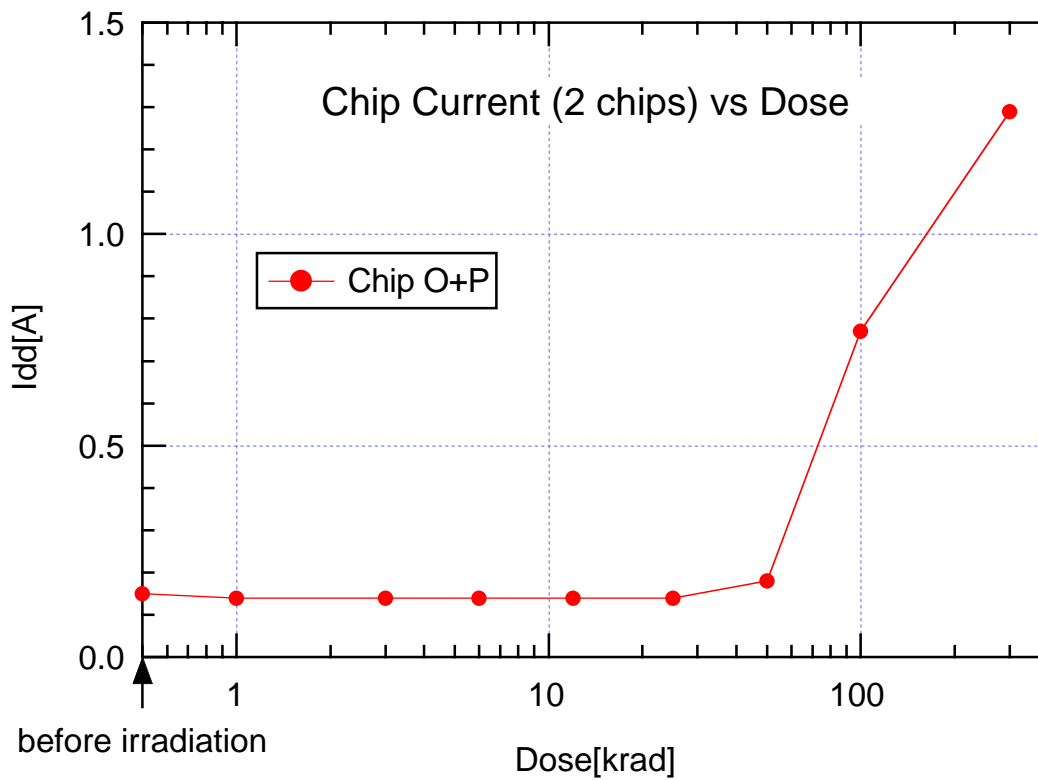
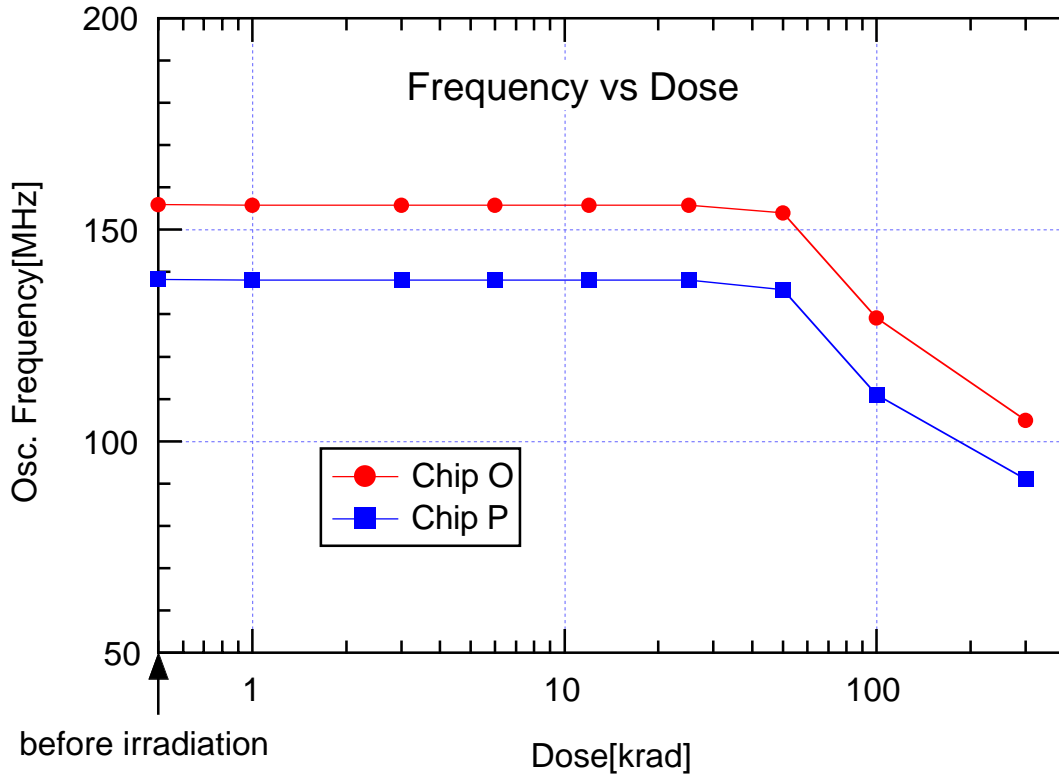
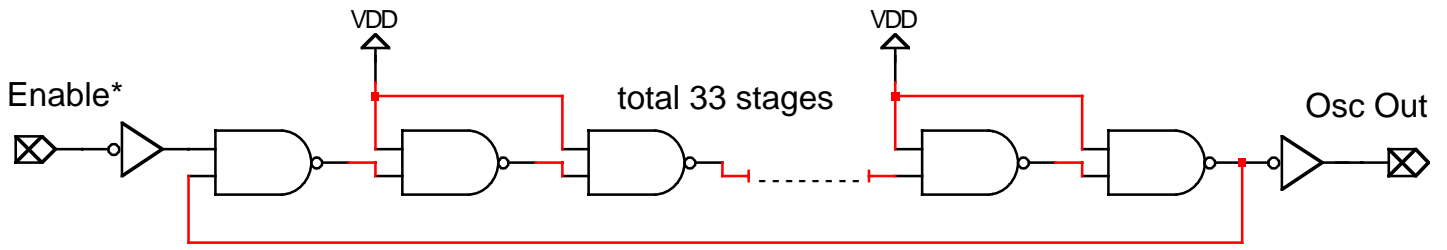
Tek Stop: 4.00GS/s ET 332983 Acqs DPO Brightness: 8 %



5 Sep 2000  
15:07:45

00.05.02 Y.A.

# AMT-TEG1 Ring Oscillator





## Summary of Measurements

	Measurements	Requirements
PLL	Freq. = 40 ~ 120 MHz Vdd = 2.8 ~ 3.8V	80 MHz 3.3V
Coarse Time Counter	120 MHz	> 80 MHz
LVDS receiver: $\Delta V$ Vcm	> 100 mV 0.2 ~ 2.2 V	> 100 mV 0.2 ~ 2.2V
LVDS driver (6.5m cable)	> 100 MHz	> 50MHz
Multiple edge resolution	< 5 ns	< 30 ns
L1B input speed	(2 + N) clocks	< (5 + N) clocks
Time Resolution	305 ps RMS	< 500 ps RMS
Diff./Int. Non-linearity	< 70 ps RMS	< 300 ps RMS
Radiation hardness for $\gamma$	> 30 krad	> 11 krad
Radiation hardness for n	> $1.6 \times 10^{13}$ n/cm <sup>2</sup>	> $1.2 \times 10^{13}$ n/cm <sup>2</sup>

## Power Consumption

### Simulation:

400 mW (Internal Circuit)  
+ 480 mW (16mW x 30 LVDS receivers)  
= ~900 mW/chip

### Measurement:

$3.3V \times 148 \text{ mA} = 488 \text{ mW/chip}$  (20mW/chan)  
(@400kHz hit, 100kHz Trigger)

### LVDS receiver:

New Low Power design will be designed at Toshiba.  
Thus more reduction in power is expected.

## Summary

- LSI technology will advance beyond year 2015.
  - Design methodology is also changing rapidly.
  - We must keep up with this change.
  - Challenge to Cost, Complexity, Testability, Radiation damage...
- 
- MDT electronics group are now making 10k channels for MDT test.
  - Start system tests in many places.
  - AMT-1 chip is working and any serious flaw is not found.
  - Final AMT chip (with Low Power LVDS receivers) will be completed in next spring.